

Notice of References Cited

Application/Control No.

10/617,186

Applicant(s)/Patent Under

Reexamination

HAGIWARA, HIDEKI

Examiner

Devona E. Faulk

Art Unit

2615

Page 1 of 1

U.S. PATENT DOCUMENTS

*	Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A US-7,190,292	03-2007	Blizjak, Karl M.	341/139
*	B US-5,680,464	10-1997	Iwamatsu, Masayuki	381/18
*	C US-6,650,755	11-2003	Vaudrey et al.	381/18
*	D US-6,501,717	12-2002	Yamazaki, Takahiro	369/47.16
*	E US-5,204,969	04-1993	Capps et al.	704/278
*	F US-5,617,480	04-1997	Ballard et al.	381/98
*	G US-5,054,077	10-1991	Suzuki, Takashi	381/109
H	US-			
I	US-			
J	US-			
K	US-			
L	US-			
M	US-			

FOREIGN PATENT DOCUMENTS

*	Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
*	N JP 04081100 A	03-1992	Japan	TANAKA et al.	H04S 7/00
*	O JP 2001218291 A	08-2001	Japan	MATSUI et al.	H04R 3/00
*	P JP 05244700 A	09-1993	Japan	TSUBONUMA, HIROSHI	H04S 7/00
*	Q GB 2264598 A	09-1993	United Kingdom	TSUBONUMA, HIROSHI	H03G 7/00
P					
S					
T					

NON-PATENT DOCUMENTS

Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)

*	U	
	V	
	W	
	X	

*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)
Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.